# **Power MOSFET**

# 80 V, 8.6 m $\Omega$ , 64 A, Single N-Channel

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFS6H850NLWF Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	80	V
Gate-to-Source Voltage	€		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	64	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C		45	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	73	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		37	
Continuous Drain			I <sub>D</sub>	14.8	Α
Current R <sub>θJA</sub> (Notes 1, 3, 4)	Steady	T <sub>A</sub> = 100°C		10.4	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.9	W
R <sub>θJA</sub> (Notes 1, 3)		T <sub>A</sub> = 100°C		1.9	
Pulsed Drain Current	T <sub>C</sub> = 25	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	308	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	61	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 3.4 A)			E <sub>AS</sub>	208	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	2.0	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	39	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

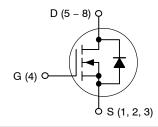


# ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
80 V	8.6 mΩ @ 10 V	64 A
80 V	11 mΩ @ 4.5 V	047

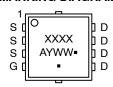
#### N-Channel





# WDFN8 (μ8FL) CASE 511AB

## **MARKING DIAGRAM**



XXXX = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
Pb-Free Package

(Note: Microdot may be in either location)

#### ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•		
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				44.2		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C			10	μΑ
		$V_{DS} = 80 \text{ V}$	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 5)	•						
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I	<sub>O</sub> = 10 A		7.1	8.6	mΩ
		V <sub>GS</sub> = 4.5 V, I	<sub>D</sub> = 10 A		8.9	11	
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub>	= 70 μΑ	1.2	1.6	2.0	V
Gate Threshold Voltage Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.2		mV/°C
Forward Transconductance	9FS	V <sub>DS</sub> = 8 V, I <sub>D</sub> = 10 A			64.1		S
CHARGES AND CAPACITANCES	•						
Input Capacitance	C <sub>iss</sub>				1450		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz}$ $V_{DS} = 40 \text{ V}$			10		pF
Output Capacitance	C <sub>oss</sub>				182		pF
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A			26		nC
Total Gate Charge	Q <sub>G(TOT)</sub>				13		1
Gate-to-Source Charge	Q <sub>GS</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A			4.0		7
Gate-to-Drain Charge	$Q_{GD}$				4.2		
SWITCHING CHARACTERISTICS (No	te 6)		•			•	
Turn-On Delay Time	t <sub>d(on)</sub>				9		ns
Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>E</sub>	oc = 64 V		21		
Rise Time	t <sub>r</sub>	I <sub>D</sub> = 10 A, R <sub>G</sub>			26		
Fall Time	t <sub>f</sub>				5		
DRAIN-SOURCE DIODE CHARACTER	RISTICS					1	
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	V
-		I <sub>S</sub> = 10 A	T <sub>J</sub> = 125°C		0.7		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dI/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 10 \text{ A}$			37		ns
Charge Time	t <sub>a</sub>				22		1
Discharge Time	t <sub>b</sub>				15		1
Reverse Recovery Charge	Q <sub>RR</sub>				40		nC

<sup>5.</sup> Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**

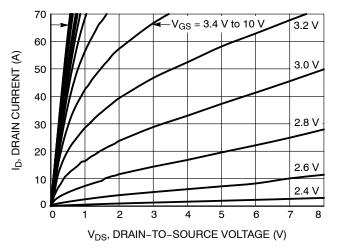


Figure 1. On-Region Characteristics

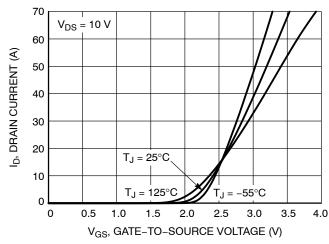


Figure 2. Transfer Characteristics

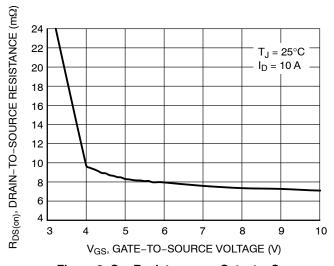


Figure 3. On-Resistance vs. Gate-to-Source Voltage

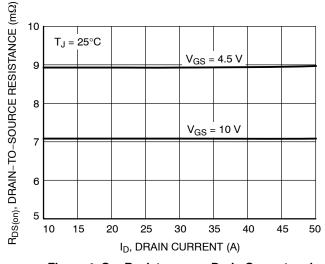


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

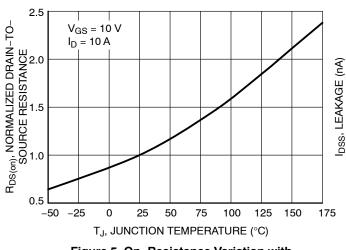


Figure 5. On–Resistance Variation with Temperature

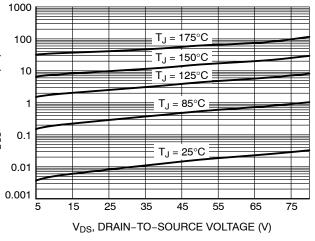


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

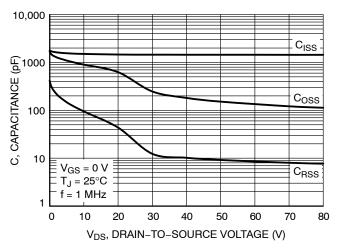


Figure 7. Capacitance Variation

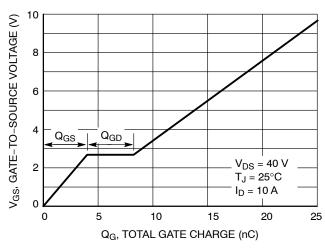


Figure 8. Gate-to-Source vs. Total Charge

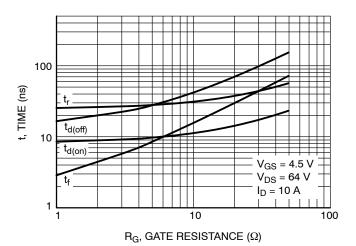


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

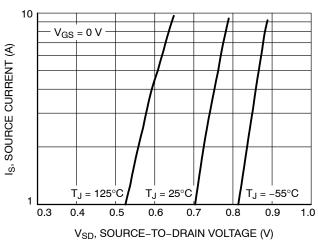


Figure 10. Diode Forward Voltage vs. Current

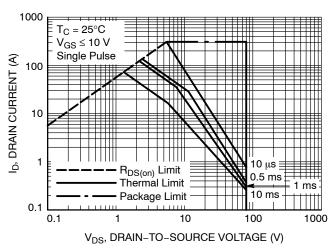


Figure 11. Maximum Rated Forward Biased Safe Operating Area

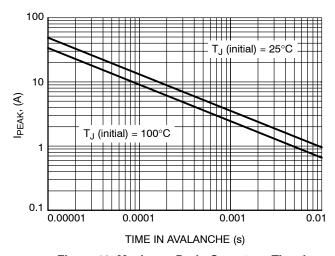


Figure 12. Maximum Drain Curent vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

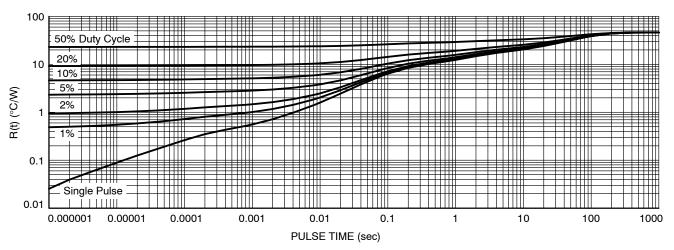


Figure 13. Thermal Characteristics

# **DEVICE ORDERING INFORMATION**

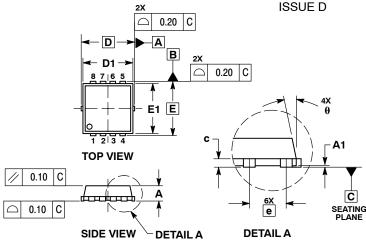
Device	Marking	Package	Shipping <sup>†</sup>
NVTFS6H850NLTAG	850L	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS6H850NLWFTAG	50LW	WDFN8 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

#### WDFN8 3.3x3.3, 0.65P

CASE 511AB

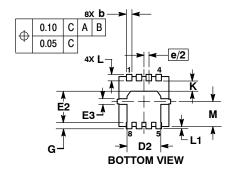


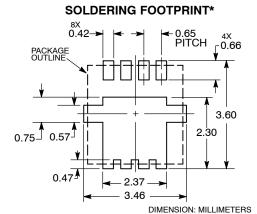
#### NOTES:

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETERS.
  3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
- PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е		0.65 BSC		(	0.026 BS0	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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